


<b>Search Notes</b>  	<b>Application/Control No.</b>  10571279	<b>Applicant(s)/Patent Under Reexamination</b>  TAKAHASHI ET AL.
	<b>Examiner</b>  Loewe, Sun Jae Y	<b>Art Unit</b>  1626

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
restriction requirement	1-4-2008	sl
stn: registry & caplus	3-18-2008	sl
palm all inventors	3-18-2008	sl

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner